

APPLICATIONS AND BENEFITS OF DXF OVERLAY APP FROM TAGARNO

The DXF Overlay app has many applications and benefits. Below is a short description of the main applications within Electronics, Material science and MedTech as well as a list of benefits that can be used during customer presentations.

Electronics

IDENTIFY PCB COMPONENTS

Localization of PCB components is one of the main advantages of the DXF Overlay app. The operator can use the search feature to locate a specific component on the DXF file and the sample itself, eliminating time spent on manually locating it.

The app can also be used for spotting deviations between the production template (the DXF file) and a current sample.



Material science

CONTOURS - GO OR NO GO?

Material science customers can use the DXF Overlay to inspect object contours and edges. If the entire object fits within the outline, the object is OK. If not, the object is a no go in its current form.

For this application, it is important that the object is flat, just like the overlay. Otherwise, it might be difficult to accurately determine the quality of the object.



Material Science

OPTIMIZE TEST WORK FLOWS

Using a DXF file with drawings of an object seen from different angles will help businesses optimize their test work flows. With the search bar, the operator can quickly switch between the drawings before rotating the object to match the drawing. The operator can then see if the product is a go or no, depending on how the sample compares to the DXF file.

With this process, the operator reduces the time spent on each sample. If a sample needs closer inspection, it can go to a second inspection stage. But by introducing this first inspection stage, the number of samples that needs to undergo a time consuming second inspection is reduced.



BENEFITS

- Improve efficiency and accuracy by using an app to easily identify/verify objects
- The overlay follows the magnification levels of the microscope, enabling visual inspection at any magnification level
- Simple and intuitive app menu that is easy to navigate and use
- Search feature eliminates wasted time spent on locating components on the overlay and sample
- With the Overlay overview, the operator can always tell what area of the DXF file they are looking at